

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	1	"20050229060"	US-PGPUB; USPAT	OR	OFF	2006/04/05 16:24
S7	220	S5 and S6	USPAT	OR	OFF	2006/04/05 16:26
S5	1002	built-in ADJ self-test	USPAT	OR	OFF	2006/04/05 16:26
S2	24	monitor ADJ built-in ADJ self-test MBIST	USPAT	OR	OFF	2006/04/05 16:26
S9	542771	monitor\$3	USPAT	OR	OFF	2006/04/05 16:29
S8	11	S5 with S6	USPAT	OR	OFF	2006/04/05 16:29
S6	280410	monitor	USPAT	OR	OFF	2006/04/05 16:29
S10	24	S5 with S9	USPAT	OR	OFF	2006/04/05 16:40
S14	33	BIST with repair with memory with redundan\$3	USPAT	OR	OFF	2006/04/05 16:42
S15	27	BIST with BISR with memory with redundan\$3	USPAT	OR	OFF	2006/04/05 16:49
S17	6	BIST with BISR with memory and redundan\$3 and timing with voltage	USPAT	OR	OFF	2006/04/05 16:51
S16	5	BIST with BISR with memory with redundan\$3 and timing with voltage	USPAT	OR	OFF	2006/04/05 16:51
S18	6	BIST and BISR and memory and redundan\$3 and timing with voltage	USPAT	OR	OFF	2006/04/05 16:52
S19	23	BIST and BISR and memory and redundan\$3 and timing and voltage	USPAT	OR	OFF	2006/04/05 16:53
S21	23	BIST and BISR and memory and redundan\$3 and timing and voltage and @ad< "20040331"	USPAT	OR	ON	2006/04/05 16:55
S24	10	BIST and BISR and memory with redundan\$3 and timing and voltage and word adj line and @ad< "20040331"	USPAT	OR	ON	2006/04/05 17:06
S27	59	BIST and BISR and memory with (row column) and @ad< "20040331"	USPAT	OR	ON	2006/04/05 17:09
S26	23	BIST and BISR and memory with bit adj line and @ad< "20040331"	USPAT	OR	ON	2006/04/05 17:09
S28	56	BIST and BISR and memory near3 (row column) and @ad< "20040331"	USPAT	OR	ON	2006/04/05 17:10
S31	2025	BIST with memory adj array redundant near (row column) and @ad< "20040331"	USPAT	OR	ON	2006/04/05 17:26

## EAST Search History

S30	26	BIST with memory adj array near3 (row column) and @ad< "20040331"	USPAT	OR	ON	2006/04/05 17:26
S33	1	BIST near3 memory adj array with redundant near (row column) and @ad< "20040331"	USPAT	OR	ON	2006/04/05 17:56
S34	5	BIST near3 redundant near (row column) and @ad< "20040331"	USPAT	OR	ON	2006/04/05 17:57
S32	10	BIST with memory adj array with redundant near (row column) and @ad< "20040331"	USPAT	OR	ON	2006/04/05 17:58
S35	21	BIST with redundant near (row column) and @ad< "20040331"	USPAT	OR	ON	2006/04/05 18:00
S40	2	"714"/\$.ccls. and instantiation near memory	USPAT	OR	ON	2006/04/06 11:42
S38	301	instantiation with memory	USPAT	OR	ON	2006/04/06 11:42
S37	3	BIST with redundant near (row column) near3 test\$3 and @ad< "20040331"	USPAT	OR	ON	2006/04/06 11:42
S39	35	instantiation near memory	USPAT	OR	ON	2006/04/06 11:43
S36	10	BIST with redundant near (row column) with memory adj array and @ad< "20040331"	USPAT	OR	ON	2006/04/06 11:48
S43	838	advantest.as. and @ad< "20040331"	USPAT	OR	ON	2006/04/06 11:49
S47	8	S43 and memory adj array and @ad< "20040331"	USPAT	OR	ON	2006/04/06 11:50
S29	41	BIST and BISR and memory adj array near3 (row column) and @ad< "20040331"	USPAT	OR	ON	2006/04/06 11:50
S48	25542	S43 and fail with memory with analysis memory adj array and @ad< "20040331"	USPAT	OR	ON	2006/04/06 11:51
S49	1	S43 and failure adj memory adj analysis and @ad< "20040331"	USPAT	OR	ON	2006/04/06 11:52
S54	1	S43 and redundant with failure near3 memory near3 analysis and @ad< "20040331"	USPAT	OR	ON	2006/04/06 11:53
S50	85	S43 and failure near3 memory near3 analysis and @ad< "20040331"	USPAT	OR	ON	2006/04/06 11:54
S56	2665	714/710-720.ccls. and BIST abd BISR and failure near3 memory near3 analysis and @ad< "20040331"	USPAT	OR	ON	2006/04/06 11:55

## EAST Search History

S58	1	714/710-720.ccls. and BIST and failure near3 memory near3 analysis and @ad< "20040331"	USPAT	OR	ON	2006/04/06 11:56
S61	7	714/710-720.ccls. and ABIST and failure near3 memory and @ad< "20040331"	USPAT	OR	ON	2006/04/06 11:58
S62	4	714/710-720.ccls. and ABIST and failure near3 memory and @pd< "20030331"	USPAT	OR	ON	2006/04/06 12:00
S64	9	714/710-720.ccls. and failure near3 map near3 bit and @pd< "20030331"	USPAT	OR	ON	2006/04/06 12:02
S65	235	714/710-720.ccls. and memory adj device and failure with memory and @pd< "20030331"	USPAT	OR	ON	2006/04/06 12:03
S67	58	714/710-720.ccls. and memory adj device and failure near1 memory and @pd< "20030331"	USPAT	OR	ON	2006/04/06 12:04
S70	6	714/710-720.ccls. and memory adj device and failure near memory and BIST and @pd< "20030331"	USPAT	OR	ON	2006/04/06 12:05
S69	7049136	714/710-720.ccls. and memory adj device and failure near memory and BISTand @pd< "20030331"	USPAT	OR	ON	2006/04/06 12:05
S68	3687169	714/710-720.ccls. and memory adj device and failure near1 memory near "2" analysis and @pd< "20030331"	USPAT	OR	ON	2006/04/06 12:05
S66	58	714/710-720.ccls. and memory adj device and failure near memory and @pd< "20030331"	USPAT	OR	ON	2006/04/06 12:05
S71	1	714/710-720.ccls. and BIST and failure near3 memory near3 analysis and @ad< "20040331"	USPAT	OR	ON	2006/04/06 12:11
S55	54	714/710-720.ccls. and failure near3 memory near3 analysis and @ad< "20040331"	USPAT	OR	ON	2006/04/06 12:11
S72	23	BIST and BISR and memory and redundan\$3 and timing and voltage and @ad< "20040331"	USPAT	OR	OFF	2006/04/06 12:14
S22	23	BIST and BISR and memory with redundan\$3 and timing and voltage and @ad< "20040331"	USPAT	OR	ON	2006/04/06 12:16
S74	2	separat\$3 with redundant adj memory and BIST with BISR and @ad< "20040331"	USPAT	OR	ON	2006/04/06 12:18

## EAST Search History

S75	1	memory adj device near3 redundant adj memory and BIST with BISR and @ad< "20040331"	USPAT	OR	ON	2006/04/06 12:21
S76	531068	memory array and redundant adj memory and @ad< "20040331"	USPAT	OR	ON	2006/04/06 12:24
S73	39	redundant adj memory and BIST with BISR and @ad< "20040331"	USPAT	OR	ON	2006/04/06 12:24
S78	250	714/710-720."ccls." and memory array near redundant adj memory and @ad< "20040331"	USPAT	OR	ON	2006/04/06 12:25
S77	1780	714/710-720."ccls." and memory array and redundant adj memory and @ad< "20040331"	USPAT	OR	ON	2006/04/06 12:25
S79	12	714/710-720."ccls." and memory array near redundant adj memory and BIST and @ad< "20040331"	USPAT	OR	ON	2006/04/06 14:53
S80	2	US-5652729-\$.DID. OR US-6483764-\$.DID.	USPAT	OR	OFF	2006/04/06 14:54
S81	18	"5652729" "6483764."	USPAT	OR	OFF	2006/04/06 14:56
S82	8	(Cochran adj William adj Hugh Hovis adj William adj Paul).in.	USPAT	OR	OFF	2006/04/06 14:58
S83	26	(Cochran adj William adj Hugh Hovis adj William adj Paul).in.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2006/04/06 15:01
S88	1	S87 and (monitor adj element).clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2006/04/06 15:02
S87	57878	(International adj Business adj Machines adj Corporation).as.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/06 15:02
S86	57878	(International adj Business adj Machines adj Corporation).as.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2006/04/06 15:02
S85	1	S83 and (monitor adj element).clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2006/04/06 15:02
S84	1	S83 and (built-in adj self-test).clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2006/04/06 15:02

## EAST Search History

S90	4	S87 and (redundant and built-in adj self-test).clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2006/04/06 15:03
S89	33	S87 and (built-in adj self-test).clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2006/04/06 15:03
S94	34	monitor ADJ built-in ADJ self-test MBIST	USPAT	OR	OFF	2006/08/22 14:17
S93	10	BIST with redundant near (row column) with memory adj array and @ad< "20040331"	USPAT	OR	ON	2006/08/22 14:17
S92	4	S91 and (redundant and built-in adj self-test).clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2006/08/22 14:17
S91	61020	(International adj Business adj Machines adj Corporation).as.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/22 14:17
S95	58	714/710-720.ccls. and memory adj device and failure near1 memory and @pd< "20030331"	USPAT	OR	ON	2006/08/22 14:18